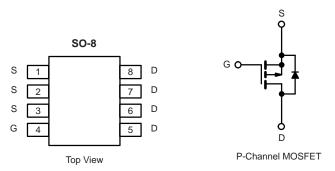


# P-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
- 40	0.010 at V <sub>GS</sub> = - 10 V	- 16.1	33 nC			
- 40	0.014 at V <sub>GS</sub> = - 4.5 V	- 13.3	33110			



#### **FEATURES**

- Halogen-free According to IEC 61249-2-21 Definition
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC



COMPLIANT HALOGEN FREE

#### **APPLICATIONS**

- Load Switch
- POL

<b>ABSOLUTE MAXIMUM RATIN</b>	IGS T <sub>A</sub> = 25 °C,	unless othe	rwise noted	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	- 40	V	
Gate-Source Voltage		$V_{GS}$	± 20	V
	T <sub>C</sub> = 25 °C		- 16.1	
Continuous Drain Current (T. – 150 °C)	T <sub>C</sub> = 70 °C	] ,	- 12.9	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	- 10.2 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		- 8.2 <sup>b, c</sup>	A
Pulsed Drain Current		I <sub>DM</sub>	- 50	A
Continous Source-Drain Diode Current	T <sub>C</sub> = 25 °C		- 5.3	
Continues Source-Drain Diode Current	T <sub>A</sub> = 25 °C	- I <sub>S</sub>	- 2.1 <sup>b, c</sup>	
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	- 28	
Single Pulse Avalanche Energy	L=0.11IIII	E <sub>AS</sub>	39	mJ
	T <sub>C</sub> = 25 °C	-	6.3	
Maximum Dawar Dissination	T <sub>C</sub> = 70 °C		4	w
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	- P <sub>D</sub>	2.5 <sup>b, c</sup>	VV
	T <sub>A</sub> = 70 °C		1.6 <sup>b, c</sup>	
Operating Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	37	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	16	20	- C/VV		

#### Notes:

- a. Based on T<sub>C</sub> = 25 °C.
  b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 85 °C/W.

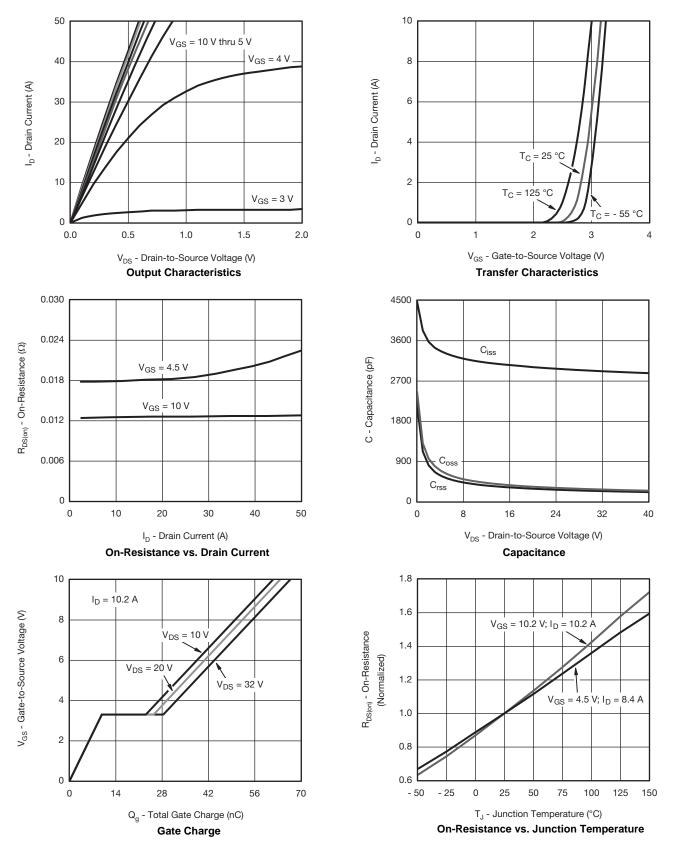


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	•				I.	•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 40			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 36		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	ι <sub>D</sub> = - 250 μΑ		5		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_{D} = -250 \mu\text{A}$	- 1.2		- 2.5	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zara Cata Valtaga Drain Current		V <sub>DS</sub> = - 40 V, V <sub>GS</sub> = 0 V			- 1	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 40 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 5	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 25			Α
Dunin Course On Otata Basistanasi	В	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 10.2 A	0.010			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = -4.5 \text{ V}, I_D = -8.4 \text{ A}$		0.014		Ω
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 10.2 A		37		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			3007		
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 20 V, V <sub>GS</sub> = 0 V, f = 1 MHz		335		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			291		
Total Cata Chausa		V <sub>DS</sub> = - 20 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 10.2 A		64	95	nC
Total Gate Charge	Q <sub>g</sub>			33	50	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = -20 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10.2 \text{ A}$		9.8		
Gate-Drain Charge	$Q_{gd}$			15.7		
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.4	2	4	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			57	86	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 20 V, $R_L$ = 2.4 $\Omega$		50	75	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 8.2 A, $V_{GEN}$ = - 4.5 V, $R_g$ = 1 $\Omega$		40	60	
Fall Time	t <sub>f</sub>			17	26	
Turn-On Delay Time	t <sub>d(on)</sub>			13	20	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 20 V, $R_L$ = 2.4 $\Omega$		11	20	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 8.2 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		45	68	
Fall Time	t <sub>f</sub>			9	18	
<b>Drain-Source Body Diode Characteristi</b>	cs					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 5.3	Α
Pulse Diode Forward Current	I <sub>SM</sub>				- 50	^
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = -8.2 A, V <sub>GS</sub> = 0 V		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			36	54	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 8.2 A, dI/dt = 100 A/μs, T <sub>J</sub> = 25 °C		41	62	nC
Reverse Recovery Fall Time	t <sub>a</sub>	I <sub>F</sub> = -8.2 A, αl/αt = 100 A/μs, I <sub>J</sub> = 25 °C		20		
Reverse Recovery Rise Time	t <sub>b</sub>			16		ns

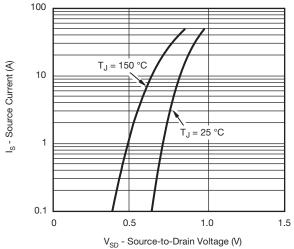
- a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %. b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

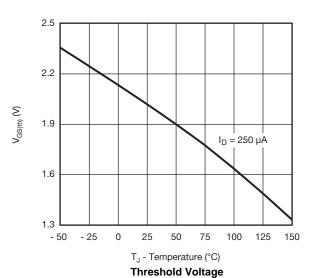






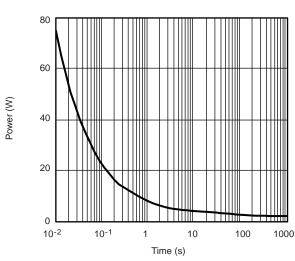


#### Source-Drain Diode Forward Voltage

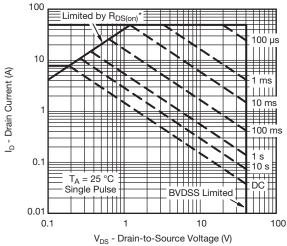


0.05
0.04
0.04
0.03  $T_{J} = 125 \, ^{\circ}\text{C}$ 0.01  $V_{GS}$  - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



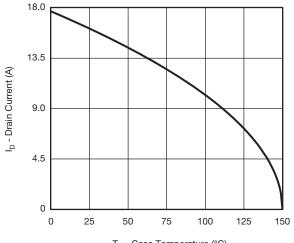
Single Pulse Power (Junction-to-Ambient)



\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

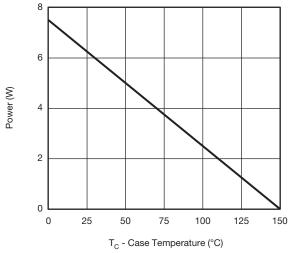
Safe Operating Area, Junction-to-Ambient

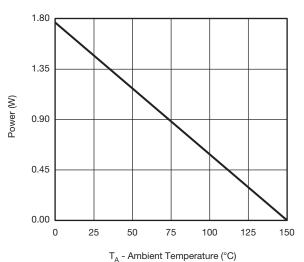




T<sub>C</sub> - Case Temperature (°C)

#### **Current Derating\***





Power, Junction-to-Foot

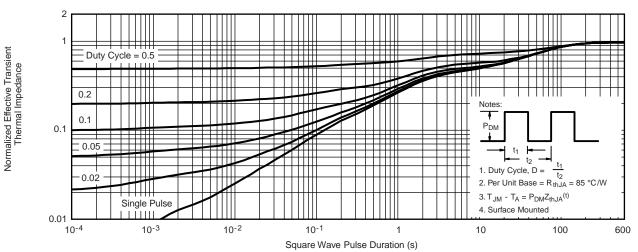
Power, Junction-to-Ambient

E-mail: China@VBsemi TEL:86-755-83251052

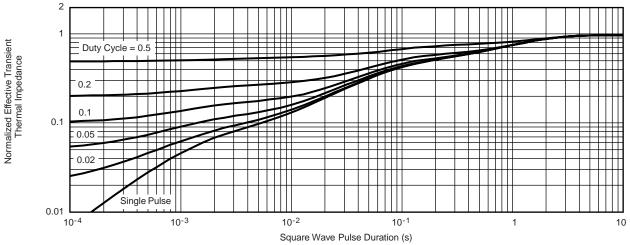
5

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

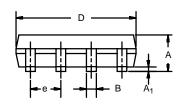
E-mail: China@VBsemi TEL:86-755-83251052

6



**SOIC (NARROW): 8-LEAD** JEDEC Part Number: MS-012





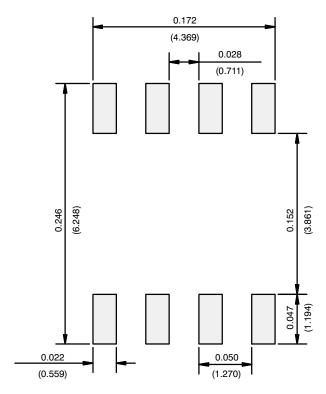


	MILLIMETERS		INC	HES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A <sub>1</sub>	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
Е	3.80	4.00	0.150	0.157		
е	1.27 BSC		0.050	0.050 BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev   11-Sen-06						

ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498



### **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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